Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/674,932	LU ET AL.	
Examiner	Art Unit	
Allen Wong	2621	

SEARCHED			
Class	Subclass	Date	Examiner
375	240	2/15/2007	AW
375	240.01	2/15/2007	AW
375	240.2	2/15/2007	AW
375	240.12	2/15/2007	AW
382	248	2/15/2007	AW
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INŢ	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
NPL search (IEEE)	2/15/2007	AW